

PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of) _		
Mohseni, et al.) For:		M FOR DIRECT ENCE SPREADING
Serial No. 10/005,453 Filed: November 2, 2001)))) Group No.	2631	NOV O 7 2002
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Assistant Commissioner of Patents Washington, D.C. 20231			NOV 0 6 2002 Technology Center 2600

Dear Sir:

Applicants submit herewith references of which they are aware in accordance with 37 CFR § 1.56.

In accordance with 37 CFR § 1.98 submitted herewith for consideration by the Examiner are the patents, publications and other information shown on the attached PTO-1449.

class mail in an envelope addressed to the Assistant Commissioner for Patents, Washington, D.C. 20231, on:

(Date of Deposit)

(Name of the Person Making Deposit)

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I hereby certify that this correspondence is being deposited with the United States Postal Service as first

The citation of these references is not intended to constitute an admission that any reference referred to herein is prior art to the invention of this application unless specifically designated as such.

The filing of this document shall not be construed to mean that any search has been made or, that if made, such search was complete or exhaustive, or that no other material information as defined in 37 CFR § 1.56 exists.

A list of the references cited herein is set forth on Form PTO-1449, which is enclosed herewith in duplicate along with a copy of each cited reference. Applicants respectfully request that the Examiner return to Applicants the enclosed copy of the Form PTO-1449 indicating consideration of the references.

The filing of this document shall not be construed to mean that any search has been made or, that if made such search was complete or exhaustive, or that no other material information as defined in 37 CFR § 1.56 exists. A list of the references is set forth on Form PTO-1449, which is enclosed herewith in duplicate along with a copy of each cited reference. Applicants respectfully request that the Examiner return to Applicants the enclosed copy of the Form PTO-1449 indicating consideration of the references. A copy of the International Search Report is also enclosed.

Respectfully submitted,

Dated: 10/29/02

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By:

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